N tic of Referenc s Cited

Application/Control No. 10/058,173	Applicant(s)/Patent Under Reexamination STEFANIK ET AL.		
Examiner	Art Unit		
Thomas D. Wang	2122	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,006,034	12-1999	Heath et al.	717/170
	В	US-6,372,974	04-2002	Gross et al.	84/609
	O	US-2002/0065868	05-2002*	Lunsford et al.	709/200
	D	US-2002/0188735	12-2002	Needham et al.	709/229
	E	US-2004/0194023	09-2004	Wiechers et al.	715/513
	F	US-6,493,871	12-2002	McGuire et al.	717/173
	G	US-6,754,895	06-2004	Bartel et al.	717/171
	Н	US-6,701,521	03-2004	McLiroy et al.	717/173
	1	US-6,782,527	08-2004	Kouznetsov et al.	717/103
	J	US-6,282,711	08-2001	Halpern et al.	717/175
	К	US-6,618,857	09-2003	Zimniewicz et al.	717/175
	L	US-6,807,559	10-2004	Budhiraja, Suresh	709/203
	М	US-6,202,207	03-2001	Donohue, Seamus Brendan	717/173

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р	**				
	α					
	R					
	ß					
	Т					

NON-PATENT DOCUMENTS

	NON-FATENT BOODINENTS				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V	3			
	w				
	x				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.